

Docket No.: 4459-131

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
Sung Mao WU *et al.* : Confirmation No. -----
U.S. Patent Application No. ----- : Group Art Unit: -----
Filed: September 23, 2003 : Examiner: -----

For: IMPEDANCE STANDARD SUBSTRATE AND METHOD FOR CALIBRATING VECTOR
NETWORK ANALYZER

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

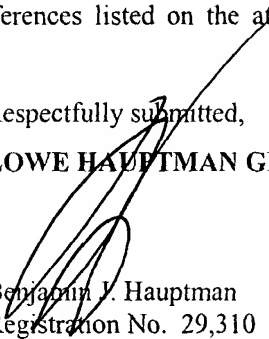
In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevancy of the references listed on the attached PTO-1449 is discussed in the present specification.

Respectfully submitted,

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Date: September 23, 2003

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| INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449) | | | | ATTY. DOCKET NO. 4459-131 | | U.S. PATENT APPLICATION NO. | |
| | | | | APPLICANT Sung Mao WU et al. | | | |
| | | | | FILING DATE September 23, 2003 | | GROUP | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| EXAMINER'S INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE | |
| | 6,348,804 | 02-2002 | Evers | | | | |
| | 5,047,752 | 09-1991 | Schorn | | | | |
| | 4,858,160 | 08-1989 | Strid et al. | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| EXAMINER'S INITIALS | PATENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
| | | | | | | Yes | No |
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| OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
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| EXAMINER | | | | DATE CONSIDERED | | | |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.